



# Technical Paper | mediaCON® USB-C Cable

**NEUTRIK®**

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## Technical Paper – mediaCON USB-C Cable

Title: NTP10

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### Subject:

This technical paper covers the general NEUTRIK USB 3.1 Type-C cable requirements of mechanical, electrical, environmental and performance characteristics.

This documentation describes the results of the test series conducted at Neutrik AG and USB-C cable manufacturer.

The tests were carried out in accordance with the following Standard regulations:

- ANSI/EIA 364-C

Electrical Connector/Socket Test Procedures Including Environmental Classifications, approved 1994. Available in hard copy – reference search site <http://www.nssn.org/information.html>

- EIA-364-1000.01

Environmental Test Methodology for Assessing the Performance of Electrical Connectors and Sockets Used in Business Office Applications

- USB 2.0

Universal Serial Bus Specification, Revision 2.0. This specification is available on the World Wide Web site <http://www.usb.org>

- USB 3.1

Universal Serial Bus Specification, revision 3.1. This specification is available on the World Wide Web site <http://www.usb.org>.

- USB Type-C

Universal Serial Bus Type-C Cable Specification, Revision 1.1 (also referred to as the USB Type-C Specification). This specification is available on the World Wide Web site <http://www.usb.org>.

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## 1 Mechanical

### 1.1 Durability Test

| Test Conditions                                                                                                                                                                         | Performance Requirement                                                                                                                                                                  |
|-----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>EIA 364-09</p> <p>The durability test shall be done at a maximum rate of 200 cycles per hour and no physical damage to any part of the connector and cable assembly shall occur.</p> | <p>For all cable assembly :</p> <p>USB Type-C: 10'000 cycles</p> <ul style="list-style-type: none"> <li>• Insertion Force: 20 N Max.</li> <li>• Extraction Force: 6 N to 20 N</li> </ul> |

### 1.2 Cable Flexing Test

| Test Conditions                                                                                                                  | Performance Requirement                                                                                                                  |
|----------------------------------------------------------------------------------------------------------------------------------|------------------------------------------------------------------------------------------------------------------------------------------|
| <p>EIA 364-41, Condition 1</p> <p>Dimension X= 3.7 times cable diameter and 100 cycles in each of two planes 120 degree arc.</p> | <ol style="list-style-type: none"> <li>1. No physical damage.</li> <li>2. No discontinuity over 1 microsecond during flexing.</li> </ol> |

### 1.3 Cable Pull-Out Test

| Test Conditions                                                                                                                  | Performance Requirement                                                                                                                                    |
|----------------------------------------------------------------------------------------------------------------------------------|------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>EIA 364-38, Test Condition A</p> <p>The cable assembly shall be subjected to a 40 N axial load for a minimum of 1 minute.</p> | <ol style="list-style-type: none"> <li>1. No physical damage.</li> <li>2. No electrical discontinuity over 1 microsecond to the cable assembly.</li> </ol> |

### 1.4 4-Axis Continuity Test

| Test Conditions                                                                                                              | Performance Requirement                                                                                                                                                                                                                               |
|------------------------------------------------------------------------------------------------------------------------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>The USB Type-C connector family shall be tested for continuity under stress using the test configurations shown below</p> | <p>Test in 4 different directions (left, right, up, down) Fixture device at 90 degree angle 8 N tensile force shall be applied to the cable in a downward direction, perpendicular to the axis of insertion, for a period of at least 10 seconds.</p> |

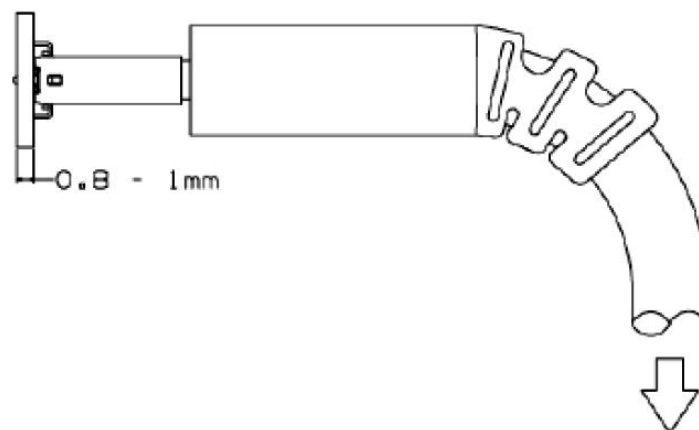


figure 1: Axis Continuity Test

## 2 Electrical

### 2.1 SuperSpeed Pair Raw Cable Differential Impedance

| Test Conditions                                                                                                 | Performance Requirement                                                                                                                                                                                                          |
|-----------------------------------------------------------------------------------------------------------------|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| The SuperSpeed pair impedance is measured at the rise time to be 200 ps (10%-90%) entering the reference plane. | For all cable assembly: <ul style="list-style-type: none"> <li>85 <math>\Omega</math> to 95 <math>\Omega</math> for Gen.2 application</li> <li>83 <math>\Omega</math> to 97 <math>\Omega</math> for Gen.1 application</li> </ul> |

### 2.2 SuperSpeed Pair Mated Connector Differential Impedance

| Test Conditions                                                                                                                                                                                | Performance Requirement                                          |
|------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|------------------------------------------------------------------|
| The differential impedance is measured at the defined rise time entering the reference plane. The definition of rise time:<br>40ps (20%-80%) for Gen.2 speed<br>50ps (20%-80%) for Gen.1 speed | For all cable assembly :<br>USB Type-C: 85 $\Omega \pm 9 \Omega$ |

## 2.3 Insertion Loss Fit at Nyquist Frequency: ILfitatNq

### Test Conditions

Normalized with mated connector  $85 \pm 9 \, \Omega$  and raw cable  $90 \pm 5 \, \Omega$  differential impedance.

### Performance Requirement

Type-C to Type-C:

- For all USB 3.1 Gen.2 pairs:  
 $\geq -4 \, \text{dB}$  at 2.5 GHz  
 $\geq -6 \, \text{dB}$  at 5 GHz  
 $\geq -11 \, \text{dB}$  at 10 GHz
- For USB 3.1 Gen.1 cable assembly:  
 $\geq -7 \, \text{dB}$  at 2.5 GHz  
 $\geq -12 \, \text{dB}$  at 5 GHz
- Type-C to Legacy Cable:  
 $\geq -4 \, \text{dB}$  at 2.5GHz,  
 $\geq -6 \, \text{dB}$  at 5GHz,
- Type-C to Legacy Adaptor:  
 $\geq -4 \, \text{dB}$  at 2.5 GHz  
 $\geq -3.5 \, \text{dB}$  at 5 GHz

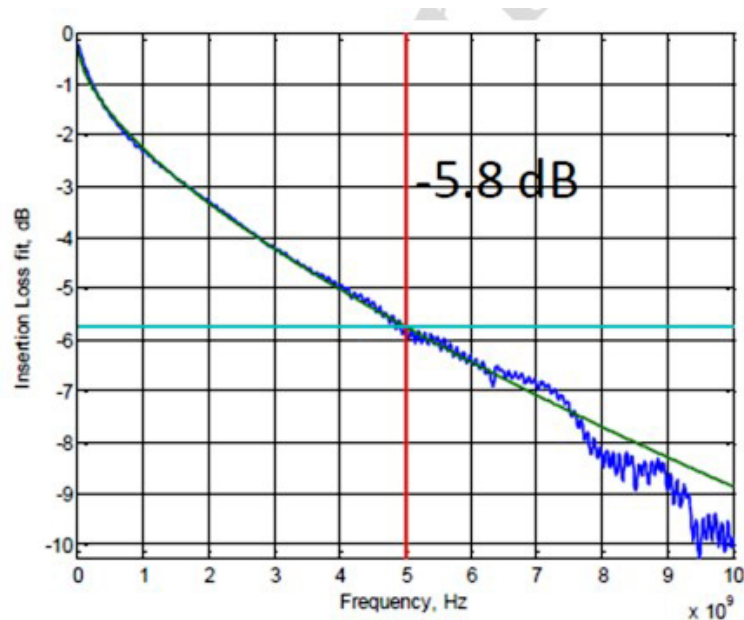


figure 2: Illustration of Insertion Loss

## 2.4 Integrated Multi-Reflection: IMR

| Test Conditions                                                                                                                                                                                                                                              | Performance Requirement                                                                                                                                                                                                                                                                                                                                                                                                                                           |
|--------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>It measures the ripple of the insertion loss, caused by multiple reflections inside the cable assembly (mated with the fixture).</p> <p>Vin(f) is the input trapezoidal pulse spectrum with Tb=Unit interval= 100 ps, Tr= 0 to 100% rise time= 0.4*Tb</p> | <p>The IMR limit is specified as a function of ILfitatNq:</p> <ul style="list-style-type: none"> <li>Type-C to Type-C:<br/> <math>IMR \leq 0.126 * ILfitatNq^2 + 3.024 * ILfitatNq - 23.392</math> in dB.</li> <li>Type-C to Legacy:<br/> <math>IMR \leq 0.126 * ILfitatNq^2 + 3.024 * ILfitatNq - 21.392</math> in dB.</li> <li>Type-C to Legacy Adaptor:<br/> <math>IMR \leq -34</math> dB for Tb=200 ps and <math>\leq -27</math> dB for Tb=100 ps.</li> </ul> |

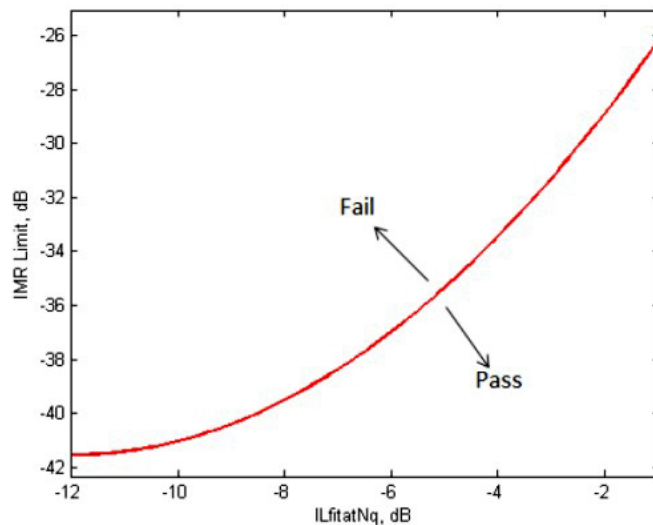


figure 3: IMR Limit as Function of ILfitatNq

## 2.5 Integrated Crosstalk on SS pairs: INEXT and ISSXT

| Test Conditions                                                                           | Performance Requirement                                                                                                                                                                                                                                                                                                                                                 |
|-------------------------------------------------------------------------------------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>The integration shall be done for each NEXT and FEXT between USB SuperSpeed pairs.</p> | <p>The IMR limit is specified as a function of ILfitatNq:</p> <ul style="list-style-type: none"> <li>Type-C to Type-C:<br/> <math>INEXT \leq -40</math> dB to 12.5 GHz<br/> <math>IFEXT \leq -40</math> dB to 12.5 GHz</li> <li>Type-C to Legacy:<br/> <math>ISSXT \leq -38</math> dB</li> <li>Type-C to Legacy Adaptor:<br/> <math>ISSXT \leq -37</math> dB</li> </ul> |

## 2.6 Integrated Crosstalk on SS pairs and D+/D- pairs: $IDDXT\_1NEXT+FEXT$ and $IDDXT\_2NEXT$

| Test Conditions                                                                    | Performance Requirement                                                                                                                                                                           |
|------------------------------------------------------------------------------------|---------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| The integration shall be done for each NEXT and FEXT between USB SuperSpeed pairs. | <ul style="list-style-type: none"> <li>Type-C to Type-C:<br/> <math>IDDXT\_1NEXT+FEXT \leq -34.5</math> dB<br/> <math>IDDXT\_2NEXT \leq -33</math> dB</li> </ul> <p>For all SuperSpeed pairs.</p> |

## 2.7 Integrated Differential Crosstalk D+/D- pairs: $IDDXT$

| Test Conditions                                                                   | Performance Requirement                                                                                   |
|-----------------------------------------------------------------------------------|-----------------------------------------------------------------------------------------------------------|
| The integration shall be done for each NEXT and FEXT between USB HighSpeed pairs. | <ul style="list-style-type: none"> <li>Type-C to Legacy Adapter:<br/> <math>\leq -23</math> dB</li> </ul> |

## 2.8 Integrated Return Loss: IRL

| Test Conditions                                                                                                            | Performance Requirement                                                                                                                                                                                                                                                                                                                                                                                                                                                                                    |
|----------------------------------------------------------------------------------------------------------------------------|------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| The integrated return loss manages the reflection between the cable assembly and the rest of the system (host and device). | <p>The IRL limit is specified as a function of <math>ILfitatNq</math> :</p> <ul style="list-style-type: none"> <li>Type-C to Type-C:<br/> <math>IRL \leq 0.046 * ILfitatNq^2 + 1.812 * ILfitatNq - 10.784</math> in dB.</li> <li>Type-C to Legacy:<br/> <math>IRL \leq 0.046 * ILfitatNq^2 + 1.812 * ILfitatNq - 9.784</math> in dB.</li> <li>Type-C to Legacy Adaptor:<br/> <math>IRL \leq -14.5</math> dB for <math>Tb=200</math> ps and <math>\leq -12</math> dB for <math>Tb=100</math> ps.</li> </ul> |

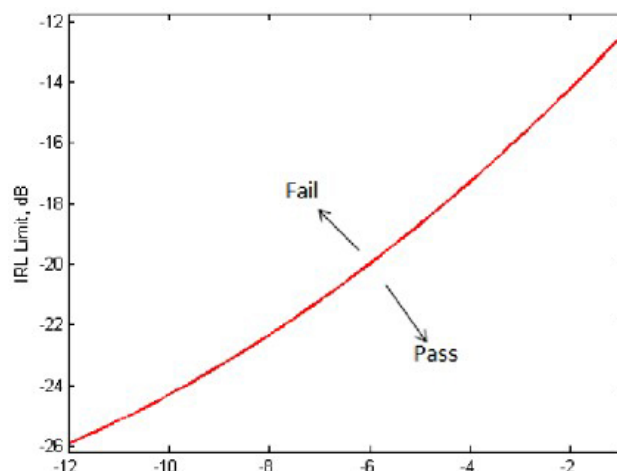


figure 4: IRL Limit at Function of  $ILfitNq$

## 2.9 Differential-to-Common Mode Conversion (SCD12/SCD21)

| Test Conditions                                                                                           | Performance Requirement                                                                                                                                                                                                                                                                                          |
|-----------------------------------------------------------------------------------------------------------|------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| Normalized with mated connector $85\pm 9\ \Omega$ and raw cable $90\pm 5\ \Omega$ differential impedance. | <ul style="list-style-type: none"> <li>Type-C to Type-C:<br/>SCD12 <math>\leq -20</math> dB from 100 MHz to 10 GHz</li> <li>Type-C to Legacy:<br/>SCD12 <math>\leq -20</math> dB from 100 MHz to 10 GHz</li> <li>Type-C to Legacy Adaptor:<br/>SCD12 <math>\leq -15</math> dB from 100 MHz to 7.5 GHz</li> </ul> |

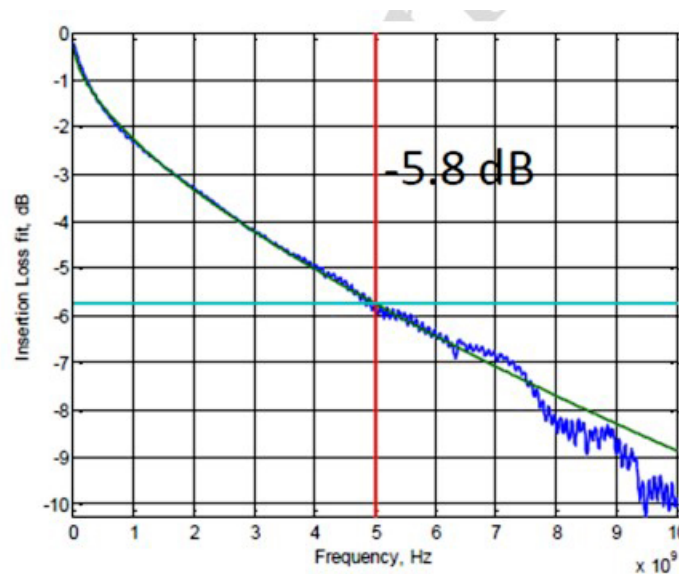


figure 5: Differential-to-Common Mode Conversion Requirement

## 2.10 D+/D- Pair Attenuation

| Test Conditions                                                                                                          | Performance Requirement                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                            |
|--------------------------------------------------------------------------------------------------------------------------|------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>EIA 364-101</p> <p>The measured frequency range should be from 50 MHz to 400 MHz with a frequency step of 10 MHz.</p> | <ul style="list-style-type: none"> <li>Type-C to Type-C:<br/> <math>\geq -1.02</math> dB at 50 MHz<br/> <math>\geq -1.43</math> dB at 100 MHz<br/> <math>\geq -2.4</math> dB at 200 MHz<br/> <math>\geq -4.35</math> dB at 400 MHz </li> <li>Type-C to Legacy:<br/> <math>\geq -1.02</math> dB at 50 MHz<br/> <math>\geq -1.43</math> dB at 100 MHz<br/> <math>\geq -2.4</math> dB at 200 MHz<br/> <math>\geq -4.35</math> dB at 400 MHz </li> <li>Type-C to Legacy Adaptor:<br/> <math>\geq -0.7</math> dB at 400 MHz </li> </ul> |



## 2.11 D+/D- Pair Differential Impedance

| Test Conditions                                                                                            | Performance Requirement     |
|------------------------------------------------------------------------------------------------------------|-----------------------------|
| The D+/D- pair impedance is measured at the rise time to be 400 ps (20%-80%) entering the reference plane. | 75 $\Omega$ to 105 $\Omega$ |

## 2.12 D+/D- Pair Propagation Delay

| Test Conditions                                                                                                                                                                                                                                  | Performance Requirement                                                           |
|--------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|-----------------------------------------------------------------------------------|
| <p>EIA 364-103</p> <p>The D+/D- pair propagation delay is measured at the rise time to be 400 ps (20%-80%) entering the reference plane.</p> <p>The propagation delay is measured at the 50% voltage crossing of the received step response.</p> | <ul style="list-style-type: none"> <li>Type-C to Type-C:<br/>20 ns max</li> </ul> |

## 2.13 D+/D- Intra-Pair Skew

| Test Conditions                                                                                                                                                                                                                                | Performance Requirement                                                                                                                                                       |
|------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>EIA 364-103</p> <p>The D+/D- pair propagation delay is measured at the rise time to be 400 ps (20%-80%) entering the reference plane.</p> <p>The intra-pair skew is measured at the 50% voltage crossing of the received step response.</p> | <ul style="list-style-type: none"> <li>Type-C to Type-C:<br/>100 ps max</li> <li>Type-C to Legacy:<br/>100 ps max</li> <li>Type-C to Legacy Adaptor:<br/>20 ps max</li> </ul> |

## 2.14 Coupling between CC and differential USB D+/D-

| Test Conditions                                                                                                                                                            | Performance Requirement                                                                                                                                                                                                                 |
|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------|-----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>EIA 364-90</p> <p>The frequency range is from 300 KHz to 100 MHz. All the measured S-parameters are single-ended with a 50 <math>\Omega</math> reference impedance.</p> | <ul style="list-style-type: none"> <li>Type-C to Type-C:<br/> <math>\leq -60.5</math> dB at 0.3 MHz<br/> <math>\leq -50</math> dB at 1 MHz<br/> <math>\leq -26</math> dB at 16 MHz<br/> <math>\leq -26</math> dB at 100 MHz </li> </ul> |

## 2.15 Coupling between VBUS and differential USB D+/D-

| Test Conditions                                                                                                                                                            | Performance Requirement                                                                                                                                                                                                                                                                                                                    |
|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------|--------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>EIA 364-90</p> <p>The frequency range is from 300 KHz to 100 MHz. All the measured S-parameters are single-ended with a 50 <math>\Omega</math> reference impedance.</p> | <ul style="list-style-type: none"> <li>Type-C to Type-C: <ul style="list-style-type: none"> <li><math>\leq -40</math> dB for <math>0.3 \text{ MHz} &lt; f \leq 30 \text{ MHz}</math>, and</li> <li><math>\leq 19.12 \log_{10}(f/30) - 40</math> (in dB) for <math>30 \text{ MHz} &lt; f \leq 100 \text{ MHz}</math></li> </ul> </li> </ul> |

## 2.16 Single ended Coupling between SBU\_A and CC,SBU\_B and CC

| Test Conditions                                                                                                                                                            | Performance Requirement                                                                                                                                                                                                                                                                        |
|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------|------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>EIA 364-90</p> <p>The frequency range is from 300 KHz to 100 MHz. All the measured S-parameters are single-ended with a 50 <math>\Omega</math> reference impedance.</p> | <ul style="list-style-type: none"> <li>Type-C to Type-C: <ul style="list-style-type: none"> <li><math>\leq -65</math> dB at 0.3 MHz</li> <li><math>\leq -55</math> dB at 1 MHz</li> <li><math>\leq -30</math> dB at 18 MHz</li> <li><math>\leq -30</math> dB at 100 MHz</li> </ul> </li> </ul> |

## 2.17 Single-ended Coupling between CC and D-

| Test Conditions                                                                                                                                                            | Performance Requirement                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                    |
|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------|--------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>EIA 364-90</p> <p>The frequency range is from 300 KHz to 100 MHz. All the measured S-parameters are single-ended with a 50 <math>\Omega</math> reference impedance.</p> | <ul style="list-style-type: none"> <li>For USB 2.0 Type-C to Type-C: <ul style="list-style-type: none"> <li><math>\leq -65</math> dB at 0.3 MHz</li> <li><math>\leq -55</math> dB at 1 MHz</li> <li><math>\leq -30</math> dB at 18 MHz</li> <li><math>\leq -30</math> dB at 100 MHz</li> </ul> </li> <li>For USB Full-Featured Type-C to Type-C <ul style="list-style-type: none"> <li><math>\leq -58</math> dB at 0.3 MHz</li> <li><math>\leq -27.5</math> dB at 10 MHz</li> <li><math>\leq -26</math> dB at 11.8 MHz</li> <li><math>\leq -26</math> dB at 100 MHz</li> </ul> </li> </ul> |

## 2.18 Single-ended Coupling between SBU\_A and SBU\_B

| Test Conditions                                                                                                                                                            | Performance Requirement                                                                                                                                                                                                                                                                                                                            |
|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <p>EIA 364-90</p> <p>The frequency range is from 300 KHz to 100 MHz. All the measured S-parameters are single-ended with a 50 <math>\Omega</math> reference impedance.</p> | <ul style="list-style-type: none"> <li>For Type-C to Type-C: <ul style="list-style-type: none"> <li><math>\leq -56.5</math> dB at 0.3 MHz</li> <li><math>\leq -46</math> dB at 1 MHz</li> <li><math>\leq -26</math> dB at 10 MHz</li> <li><math>\leq -25</math> dB at 11.2 MHz</li> <li><math>\leq -25</math> dB at 100 MHz</li> </ul> </li> </ul> |

## 2.19 Coupling between SBU\_A / SBU\_B and differential USB D+/D-

| Test Conditions                                                                                                                                             | Performance Requirement                                                                                                                                                                                                                         |
|-------------------------------------------------------------------------------------------------------------------------------------------------------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| EIA 364-90<br><br>The frequency range is from 300 KHz to 100 MHz.<br>All the measured S-parameters are single-ended with a 50 $\Omega$ reference impedance. | <ul style="list-style-type: none"><li>For Type-C to Type-C:<ul style="list-style-type: none"><li><math>\leq -80</math> dB at 0.3 MHz</li><li><math>\leq -40</math> dB at 30 MHz</li><li><math>\leq -40</math> dB at 100 MHz</li></ul></li></ul> |

## 2.20 Voltage Drop Test

| Test Conditions                                                                                    | Performance Requirement                     |
|----------------------------------------------------------------------------------------------------|---------------------------------------------|
| The maximum rated VBUS current of the cable assembly shall be used.                                | 250 mV max for GND and 500 mV max for VBUS. |
| The measurement includes receptacles at both ends of the cable assembly, mounted on test fixtures. |                                             |

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